

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE 0 11 JUN 2006

In re the Application of

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Hiroyuki NAGASAKA et al.

Application No.: New U.S. National Stage of PCT/JP2004/018435

Filed: June 1, 2006 Docket No.: 128253

For: EXPOSURE APPARATUS, EXPOSURE METHOD, METHOD FOR PRODUCING DEVICE, AND OPTICAL PART

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of one or more non-English language reference is discussed in the present specification. See References <u>10-11</u>.
- 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 1 & 8-13.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 5. An English language Translation of one or more non-English language reference is attached hereto. See References 10 & 26-27.
- 6. An English language Abstract of one or more non-English language reference is attached hereto. See References 8-27.
- 7. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See References 8-13, 16-17 & 22-27.

New U.S. National Stage of PCT/JP2004/018435

## SECULION 2006

 $\boxtimes$  8. Reference <u>1</u> corresponds to reference <u>9</u>.

Respectfully submitted,

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Date: June 1, 2006

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Form PTO-1449 US Dept. of Commerce APPLICATION NO. ATTY DOCKET NO. (REV. 1/06) PATENT & TRADEMARK OFFICE 128253 INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) **APPLICANTS** Hiroyuki NAGASAKA et al. FILING DATE June 1, 2006 **U.S. PATENT DOCUMENTS** Examiner Cite Document Number Date Initials No. Name YAMAGUCHI et al. 2003/0139620 A1 07/24/2003 1. 2. 5,825,043 **SUWA** 10/20/1998 3. 4,346,164 TABARELLI et al. 08/24/1982 4,480,910 11/06/1984 4. TAKANASHI et al. 5. 5,610,683 03/11/1997 TAKAHASHI 5,715,039 6. FUKUDA et al. 02/03/1998 7. 2004/0165159 A1 08/26/2004 LOF et al. FOREIGN PATENT DOCUMENTS Examiner Cite With With Initials No. Document Number Country English English Date Abstract **Translation** 8. JP-A-2003-240906 08/27/2003 **JAPAN** X X 9. JP-A-2003-238577 08/27/2003 **JAPAN** X X 10. WO 99/49504 A1 X 09/30/1999 WIPO X 11/13/1998 **JAPAN** 11. JP-A-10-303114 X X JP-A-11-176727 12. 07/02/1999 **JAPAN** X X JP-A-2004-207711 07/22/2004 **JAPAN** 13. X X JP-A-04-305915 10/28/1992 **JAPAN** 14. X JP-A-04-305917 10/28/1992 **JAPAN** 15. X JP-A-10-340846 12/22/1998 **JAPAN** X 16. X JP-A-2000-058436 02/25/2000 **JAPAN** X 17. X JP-A-63-157419 06/30/1988 **JAPAN** X 18. **OTHER DOCUMENTS** Cite Examiner (Including Author, Title, Date, Pertinent Pages, etc.) Initials No. **EXAMINER DATE CONSIDERED** Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance Examiner: and not considered. Include copy of this form with next communication to applicant.

Date: June 1, 2006

## AP20 Rec'd PCT/PTQ of 1, JUN 2006

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO.  128253  APPLICATION NO.  New U.S. National  Stage of 1 3 0 7					
INFORMATION DISCLOSURE STATEMENT							Pef/JP200	04/618433	
(Use several sheets if necessary)				APPLICANTS Hiroyuki NAGASAKA et al.					
				FILING June 1,					
U.S. PATENT DOCUMENTS									
Examiner Initials	Cite No.	Document Number	Date			Name			
FOREIGN PATENT DOCUMENTS									
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	19.	JP-A-58-202448	11/25/1983		JAPAN		x		
	20.	JP-A-59-019912	02/01/1984		JAPAN		х		
	21.	JP-A-62-065326	03/24	/1987	JAPAN		x		
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	28.	WO 2004/019128 A2	03/04	/2004	WIPO				
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